JAN-09-2004	16:41	WELLS ST	.JOHN, P.S.			50983	33424	P.03/0
Funn PTO-1419		U.S P.V	E DEPARTMENT OF COMMERCE IVATI AND THADEMARK OFFICE	ATTY, DOTRETNO. Mizz-2438		SERI.	1.NO.	
	LIST OF ART CITED	BY APPLICAN	٧T	APH JCANT				
				FILING DATE November 3, 2003		CRO1 2615	iP	
			U.S. PATENT DOCUMENTS					
*Examines Inicial	Decement Number	Date	Nime		Class	Sulaten	Filing If Appe	damie Dato
AG M	6.171.900 B1	01-2001	Sun					
AB								
^~					ļ	/		
, LIN								
Als								
AF								
AG								
All								
A								
Ŋ	_						ļ	i
AK		ļ						
AL	<u></u>	<u> </u>	LX.		L	ļ	<u></u>	
	1_		PHEREN PARENT DOCUMENTS		~	T	Γ	
	Document Number	Date	Соетту		Clas	Subriss	Tearabeira	No
AM			<u> </u>	 -		<u> </u>		
AN'	l	1						
AP								
AQ		<u> </u>		$\overline{}$		L		
		OTHER REPER	NCES (including Author, Tiele, Date, F	eriment Pages, Bid)				
AR					\			
					$\overline{}$			
As						/_		
_/ _		-				$\overline{}$		
/ AT							$\overline{}$	
	111	1		1 ,		<u></u>	$\overline{}$	
EXAMENER /	Duff COSSIDERE	a	4/26/	04				7
*EXAMINER: Initialifie	ference pansidered, where or a	es ni ti noitais tuc	phymonoa with MPEP 60% Draw lis	so through viction if not	in conferman	ce and not con	idered. Include	copy of

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PRIORI PATENT AND TRADEMARK OFFICE M122-2438 09(602,381									IORITY	
		LIST OF ART CITED (Use several sheet		:	APPLICANT Micron Technology	, loc.			•	•
					FILING DATE PR	IORITY		GRO 2815	UP PRIORI	TY .
			·	U.S. PATENT DOCUMENTS						
*Examiner Initial A		Document · Number	Date	Name		Class	Sub	class	Filio If App	g Date ropriate
AP	AA	5,032,545	07-1991	Dozn et al.					·.	
	AB	5,436,481	07-1995	Egawa et al.					,	
	AC	5,378,645	01-1995	Inoue et al.						
	AD	5,258,333	11-1993	Shappir et al.						
	AE	5,518,946	05-1996	Kuroda	•					_
	AF	5,445,999	08-1995	Thakur et al.				٠٠,	. 14	
<u>.</u> ,	AG	5,382,533	01-1995	Ahmad et al.				,	. >	
F. (* * 1	АН	5,663,077	09-1997 .	Adachi et al		÷ .		,н		٠.
777-1	Al	5,026,574	- 206-1991×	Economu et al., 🛥	÷. •			h	; þ.	٠
	AJ	5,612,558	03-1997	Harshfield	erdinaer sweeth			٠.		· · / ·
ar ner i rekend	AK	5,719,083	02-1998	Komatsu	ens ng. n nngn . tuan		- ; -	÷į	. 1	
AC	. AL	5,760,475	06-1998	Cronin	•			ä.	* -	· ·
7.40	^· ·		da or er j	FOREIGN PATENT DOCUMEN	13	• 7				
		Document : Number	. Date	· Country ·	·.	Class	. ·Sub	class	Trar Yes	station No
AC	АМ	WO 96/39713	12-1996	PCT						
NO	AN-		•					,		
	AO									14.
	AP			·	·		_			<u> </u>
	AU		<u> </u>	i						
		от	HER REFEREN	CES (including Author, Title, Date	, Pertinent Pages, Etc.)	•				•
AP	AR	Wolf, S., "Silicon"	Processing for th	e VLSI Era", Lattice Press 1990	, Vol. 2, pp. 212-213.			•		:
JU								•		
AC	AS	Wolf, S., "Silicon	Processing for th	e VLSI Era*, Lattice Press 1990	, Vol. 2, pp. 188-189,	194-195, 60	19-614,		· · · · · · · · · · · · · · · · · · ·	· · · · · · · · · · · · · · · · · · ·
Do	AT	Ko, L. et al., "Th	e Effect of Nitro	gen Incorporation into the Gate	Oxide by Using Shall	low Implants	ation o	of Nitro	gen and Dr	ve-In
NO	,	Process*, IEE	E 1996, pp. 32-33	57						
EXAMINER	//	My S	LL	DATE CONSIDER	ED 4	126	/	00	7	
*EXAMINER: considered, In	Initial include co	if reference considered, whe	ther or policitation	on is in conformance with MPE	P 609; Draw line thro	ugh citation	if not	in coa	formance as	id nos

Form PTO-14	49			U.S. D PATEN	EPARTMENT OF COMMERCE IT AND TRADEMARK OFFICE	ATTY. DOCKET N	NO.	SERIAL NO. PRIORITY 09/602,381			
			LIST OF ART CITED E			APPLICANT Micron Technology,	lnc.				
						FILING DATE PR June 22, 2000	IORITY		GROU 2815	JP PRIORIT	Y
					U.S. PATENT DOCUMENTS						
*Examiner Initial A		Docu Numi	oment ber	Date	Name		Class	Subo	class	* Filing If Appro	Date opriate
AC	AA	5,834	1,372	11-1998	Lee						
	АВ	5,619	0,057	04-1997	Komatsu						
	AC	5,633	1,036	05-1997	Seebauer et al.						
	AD	6,054	,396	04-2000	Doas	,	•				
	AE	6,174	i,821	01-2001	Doan		:			•	
	· AF	5,939	7,750	08-1999	Early			;		٠.,	
	AG	5,254	1,489	10-1993	Nakata						
	AH ·	5,464	1,792	11-1995	Tseng et al.						
	Al	5,620	1,908	04-1997	Inoh et al.				·	: .	
	AJ	5,716	i,864	02-1998	Abe						
·	AK,	5,972	2,783	10-1999	Arai et al.	•	i .				•
A	· AL	6,093	,661	07-2000	Trivedi et al.						
40		,			FOREIGN PATENT DOCUMEN	TS	I	1			
		Docu Num	imeni ber	Date	Country		Class	Subt	1853	Transl Yes	ation No
	AM	┢								. '	110
	AN										
	AO									•	
	AP	<u> </u>				1					
	AQ					1]		
			. оп	ier referenc	CES (including Author, Title, Date	, Pertineat Pages, Etc.))				
No	AR		Doyle, B. et al., "S	simultaneous Gr	owth of Different Thickness Gate	e Oxides in Silicon C	MOS Proces	ssing".	EEE V	/ol. 16 (7), J	uly 1995.
1756			рр. 301-302.								
10	AS		Kuroi, T. et al., "I	he Effects of N	itrogen Implantation Into P+Pol	y-Silicon Gate on Ga	ie Oxide Pr	opertie:	s°, 1994	Sympos. on	VLSI
MC			Technology Dig	est of Technical	Papers, IEEE 1994, pp. 107-108	•					
A	АТ		Liu, C.T. et al., "N	Aultiple Gate O	ride Thickness for 2GHz System-	on-a-Chip Technologi	es", IEEE 1	998, p	p. 589-5	592.	•
. 10]		,	1	1		/				
EXAMINER	7	M	Le U	M L	DATE CONSIDER	ED 4/0	26	10	14	<u></u>	
*EXAMINER: considered. 1	Initia) nclude co	if refere	nce considered, when	ner or not ditation	on is in conformance with MPEI	P 609; Draw line thro	ough citation	if not	in con	formance and	not

Form PTO-14	49			U.S. D PATEN	EPARTMENT OF COMMERCE	ATTY, DOCKET N M122-2438	NO.		SERIAL NO. PRIORITY 09/602,381			
		1	LIST OF ART CITED I			APPLICANT Micron Technology.	, loc.			:		
			•			FILING DATE PR		GRO 2815	UP PRIORIT	Y		
					U.S. PATENT DOCUMENTS	74HE 22, 2000		1 2013	-	_		
*Examiner		Docu Numi	ment	Date	Name		Class	Subclass	Filing If Appro			
De	ÄA	5,994	,749	11-1999	Oda							
1	АВ	5,674	1,788	10-1997-	Wristers et al.							
	AC	5,596	i,218	01-1997	Soleimani et al.			_	:			
	AD	5,960),302	09-1999	Ma et al.							
	AE	6,207	7,532 Bi	03-2001	Lia et al.							
·	AF	6,114	,203	09-2000 ·	Ghidini et al.			:				
	AG	6,110	0,842	08-2000	Okuno et al.			:				
	АН	6,091	.110	07-2000	Hebert et al.			:	;			
	Al	5,330	920	07-1994	Soleimani et al			•				
	AJ	6,140),187	10-2000	DeBusk et al.				· · · · · ·	•		
	AK	6,197	7,701	03-2001	Shue et al.				:			
Al	AL	6,091	,109	07-2000	Hasegawa				:			
ļ	T -			, ,	FOREIGN PATENT DOCUMEN	TS	<u> </u>		· [•			
		· Docu Num	iment ber	Date	Country		Class	Subclass	Yes	lation No		
	AM			·						,		
	AM		•									
_	AO									•		
	AP											
	AQ											
		-	OTI	HER REFEREN	CES (including Author Hile, Date	e, Pertinent Pages, Etc.))					
	AR									•		
				$\overline{}$								
	AS								•	-		
				-								
	W				4							
				1 //				•				
EXAMINER	1	L	Y	10	DATE CONSIDER	RED 4	/26	10	4			
*EXAMINER considered.	: Initial	if refere	ence considered, when	her or not citati mmunication to	on is in conformance with MPE applicant.	P 609; Draw line thro	ough citation	If not in co	nformance and	d not		

Form PTO-14	49		U.S. D PATEN	EPARTMENT OF COMMERCE	ATTY, DOCKET N MI22-2438	₹0.		AL NO. PRI 2,381	ORITY
		LIST OF ART CITED			APPLICANT Micron Technology	l Inc.			
					FILING DATE PR June 22, 2000		GRO 2815	UP PRIORIT	Y
	- <u>-</u>			U.S. PATENT DOCUMENTS					
Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing If Appre	Date opriate
Ae	AA	6,080,682	06-2000	lbok					
Ĭ	АВ	5,685,949	11-1997	Yashima					
	AC	6,268,296 B1	07-2001	Misium et al.			•		:1
	AD	6,232,244 B1	05-2001	lbok					
	AE	6,255,703 B1	07-2001	Hause et al.	•				•
	AF	6,274,442 B1	08-2001	Gardner et al.					·:
	AG	6,228,701 B1	05-2001	Dehm et al.		:			
	AH	6,136,636	10-2000	Wu .				:	
	Al	6,033,998	03-2000	Aronowitz et al.				; ;	•
	AJ.	6,057,220	05-2000	Ajmera et al.				₹.	
M	AK	.6,087,229,	07-2000	Aronowitz et al.				1 2.	
AC.	AL	5,998,253	12-1999	Loh et al.			<u> </u>		
				FOREIGN PATENT DOCUMEN	TS		I	1.	
		Document · Number	Date	Country		Class	Subclass	T .	tation
		•						YES	No
	AM							 	
	AN		<u> </u>				 		
	AO				/_			-	
	AP		<u> </u>			· · · · · · · · · · · · · · · · · · ·		 	
	AQ	ļ				l	l	:	
		ОТ	HER REFEREN	CES (including Author, Title, Date	, Pertinent Pages, Etc.	_			
	· AR ·	range of the second	/				$\overline{}$. ;	
	.	 	/						
	AS								
,						· #			
	АТ				-				
				/		,	,		
EXAMINER		1/1/4	W.	DATE CONSIDER	EED 4/	26/	104	/	
EXAMINER	: Initial i	f reference considered, whe	the or not city	on is in conformance with MPE applicant.	P 609; Draw line thro	ough citation	if not in co	nformance an	d not
IDIUEIEG. I	meinne col	yy or this torin with next to	y munication (approant.					

Form PTO-14	49		U.S. D PATEN	EPARTMENT OF COMMERCE	ATTY. DOCKET NO. SERIAL NO. PRIORITY 09/602,381				
·		LIST OF ART CITED E (Use several sheets			APPLICANT Micron Technology	. Inc.			:
		· · ·			FILING DATE PR June 22, 2000	IORITY		OUP PRIORI	TY
		•		U.S. PATENT DOCUMENTS			_		
*Examiner Initial		Document Number	Date	Name	-	Class	Subclass	Filia If App	g Date ropriate
AP	AA	5,763,922	06-1998	Chau					
	AB	6,225,167 B1	05-2001	Yu et al.					
	AC	5,960,289	09-1999	Tsui et al.					
	AD	5,972,800	10-1999	Hasegawa					
	AE	6,146,948	11-2000	Wu et al.				1	
	AF	6,362,085	03-2002	Yu et al.				1	
	AG	5,164,331	11-1992	Lin et al.				1	
	НА	5,318,924	06-1994	Lin et al.				.	
	ΑI	5,449,631	09-1995	Giewont et al.					:
	ΙA	5,518,958	05-1996	Giewont et al.	•				
	AK	6,201,303	03-2001	Ngo et al.					
AG	AL	6,399,445	06-2002	· Hattangady et al.					
		-	·	FOREIGN PATENT DOCUMEN	гѕ				
		Document . Number	Date	· Country		Class	Subclass		slation
	АМ	• •						Yes	No .
	AN								
	AO								(
	AP								
	AQ							1	
	_ רע	ОТН	IER REFERENC	CES (Including Author, Title, Date	Pertinent Pages, Etc.)			<u> </u>	1
• • • • •	· AR	- 1		- 1				:-	
.,					·				
	AŚ				· · · · · · · · · · · · · · · · · · ·		•		
			·						
	AT							·····	·
				/		/			
EXAMINER	7	All C	The state of the s	DATE CONSIDER	ED 4/	261	109	1	
*EXAMINER:	Initial if	reference considered, whether	ner or not citriis	n is in conformance with MPEF	609; Draw line thro	ugh citation	if not in c	onformance ar	d not

Form PTO-14	49		U.S. D.	EPARTMENT OF COMMERCE	ATTY, DOCKET I	NO.	SER 09/60	SERIAL NO. PRIORITY 09/602,381			
		LIST OF ART CITED I (Use several sheets			APPLICANT Micron Technology,	, Inc.					
					FILING DATE PR June 22, 2000	IORITY	GRC 2815	UP PRIORITY			
				U.S. PATENT DOCUMENTS		-					
*Examiner (bitial		Document Number	Date	Name	_	Class	Subclass	Filing Date If Appropriate			
AC	AA	6,331,492 B2	12-2001	Misium et al.							
	, AB	6,080,629	06-2000	Gardner et al.							
	AC	5,970,345	10-1999	Hattangady et al.					ı		
	AD	5,885,877	03-1999	Gardner et al.	4			·			
	AE	6,323,114 B1	11-2001	Hattangady et al.							
	AF	6,184,110 B)	02-2001	Ono et al.							
	AG	5,837,598	11-1998	Aronowitz et al.				,			
	АН	6,450,116	09-2002	Noble et al.				Vi. 1			
	Al	4,605,447	08-1986	Brotherton et al.				· ;			
	AJ	6,207,586	03-2001	Ma ct al.	•			;·-			
N	AK	5,837,592	11-1998	Chang et al.							
K	AL	5,334,554	08-1994	Lin et al.							
			1	FOREIGN PATENT DOCUMEN	TS	ı					
		Document Number	Date	Country		Class	Subclass	Translation Yes No	_		
	AM							- N			
	/2										
	AO				•						
	AP										
	AQ										
		оті	HER REFERENCE	CES (including Author, Title, Date	Pertinent Pages, Etc.)					
	AR -						:	,			
			_					<u> </u>			
	AS						-				
	AT										
	Ţ				•	/	,				
EXAMINER	1	Mh.	1/4	DATE CONSIDER	RED 4/2	06/1	94				
*EXAMINER: considered. I	Initial i	if reference considered, when	her or not citati	on is in conformance with MPE applicant.	P 609; Draw line thro	ough citation	if not in co	aformance and not			

Form PTO-14	49		U.S. D	EPARTMENT OF COMMERCE	ATTY. DOCKET I M122-2438	NO.	SER1 09/60	AL NO. PRI 2,381	DRITY
		LIST OF ART CITED E (Use several sheets			APPLICANT Micron Technology	, Inc.			
		· · · · · · · · · · · · · · · · ·			FILING DATE PR June 22, 2000	JORITY'	GRO 2815	UP PRIORIT	ν
				U.S. PATENT DOCUMENTS					
*Examiner Initial	4	Document Number	Date	Name		Class	Subclass	Filing If Appr	Date opriste
DE	AA	6,297,162	10-2001	Jang et al.					
	AB	6.436,771 B1	08-2002	Jang et al.					
	AC	6,413,881	07-2002	Aronowitz et al.					
	AD	6,110,780	08-2000	Yu et al.					
	AE	5,861,651	01-1999	Brasen et al.					
	AF	5,840,610	11-1998	Gilmer et al.					
	AG	5,500,380	03-1996	Kim				:	
	АН	6,410,991 B1	06-2002	Kawai et al.	í				
	- Al	6,482,690 B2	11-2002	Shibata					
	AJ ,	6,492,690 B2	12-2002	Ueno et al.					
A6	AK	6,399,448	06-2002	Mukhopadhyay +				٠١.	
\ \ \ \	AL .								
			. 1	FOREIGN PATENT DOCUMEN	TS				
,		Document Number	Date	Country		Class	Subclass	Trans	lation
			•					Yes	No
	AM				•				
	AN			· · · · · · · · · · · · · · · · · · ·					
	AO							ļ	
	AP							ļ	
	AQ								
		отн	IER REFEREN	ES (including Author, Title, Date	Pertinent Pages, Etc.				
	AR .			•					
								_	
•									1
	AS		_						
	^^° }	1 /	}						
	\bot	la .	1						
EXAMINER	[]	the M	1	DATE CONSIDER	ED. 4/	26/1	24		
*EXAMINER: considered. In	Initial i	f reference considered whether	ner or nor statio	on is in conformance with MPEI	P 609; Draw line thro	ugh citation i	if not in co	nformance and	l not .